



Accelerator Beam Physics Group
BE department

BEAM CHARACTERIZATION IN LINAC4

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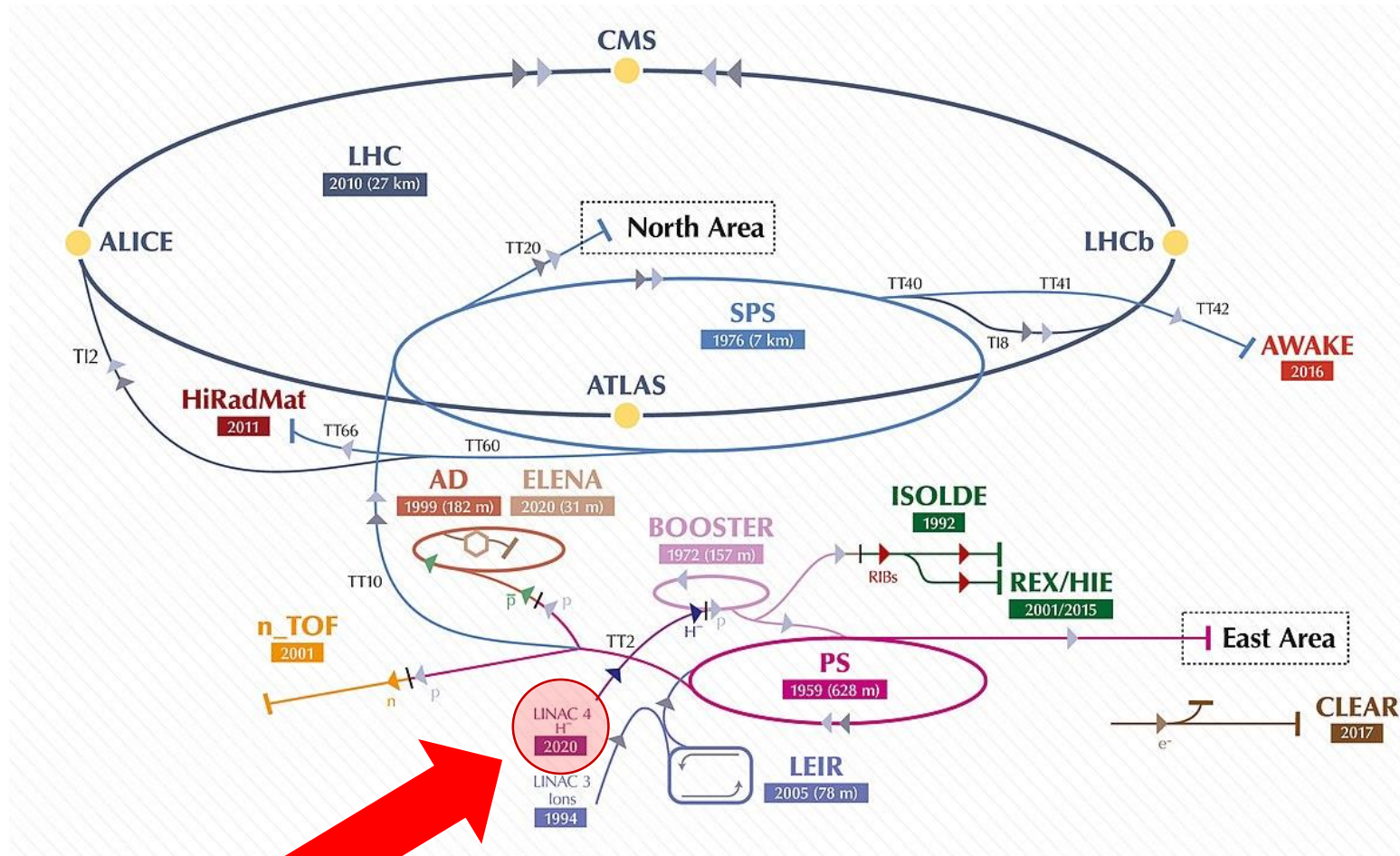
With the Support of: Jonathan Bollig, Edgar Sargsyan, Jone Etxebarria Erdoiza



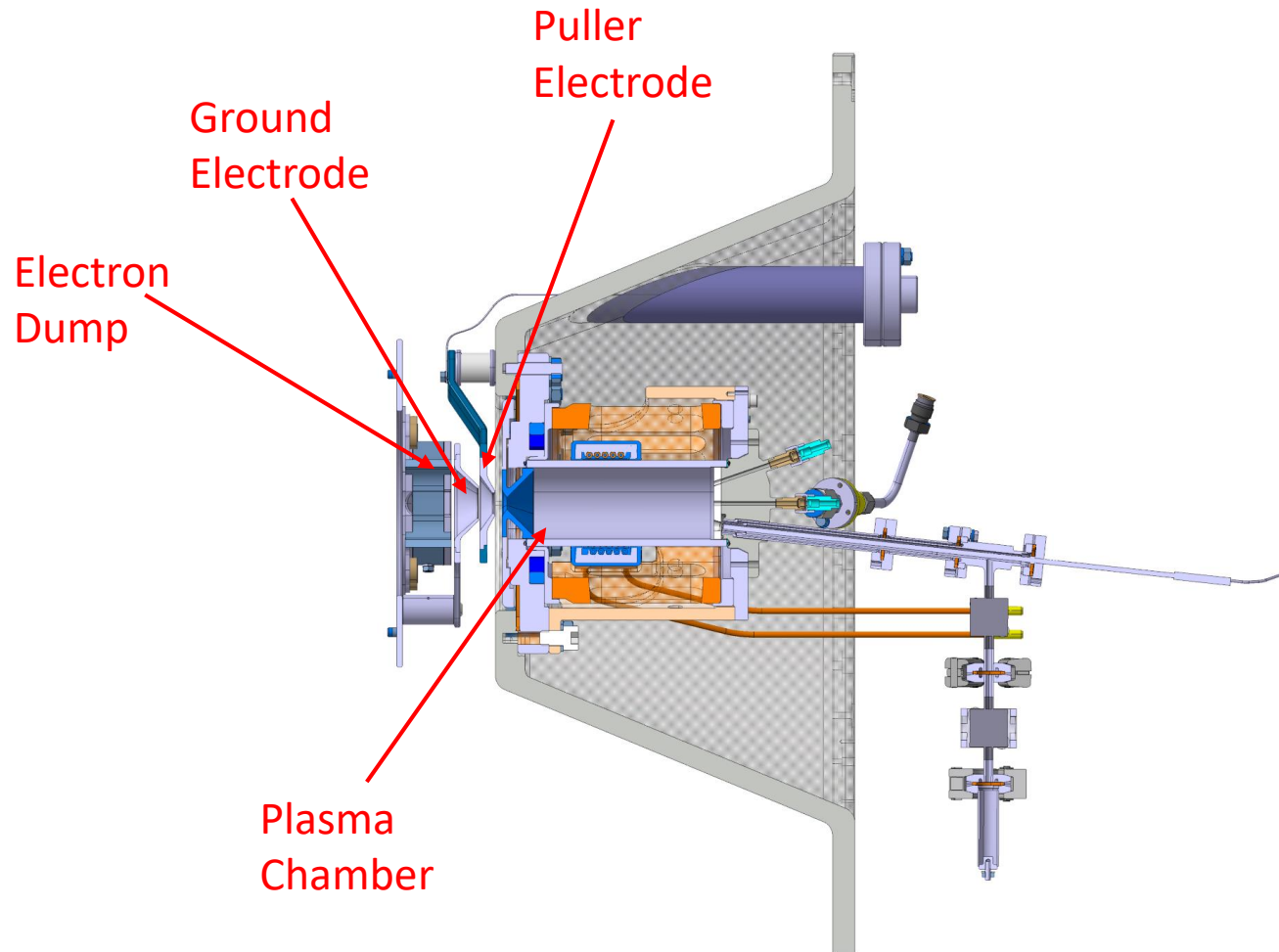
Table of Contents

1. Introduction of LINAC4 ion source
2. Verification of the Combiner Codes
3. Particle Tracking Using TRAVEL
4. Emittance Analysis
 - a. Current Method + Issues
 - b. SCUBEEEx Method
 - c. Current Progress
5. Future Works

LINAC4 as the Injector

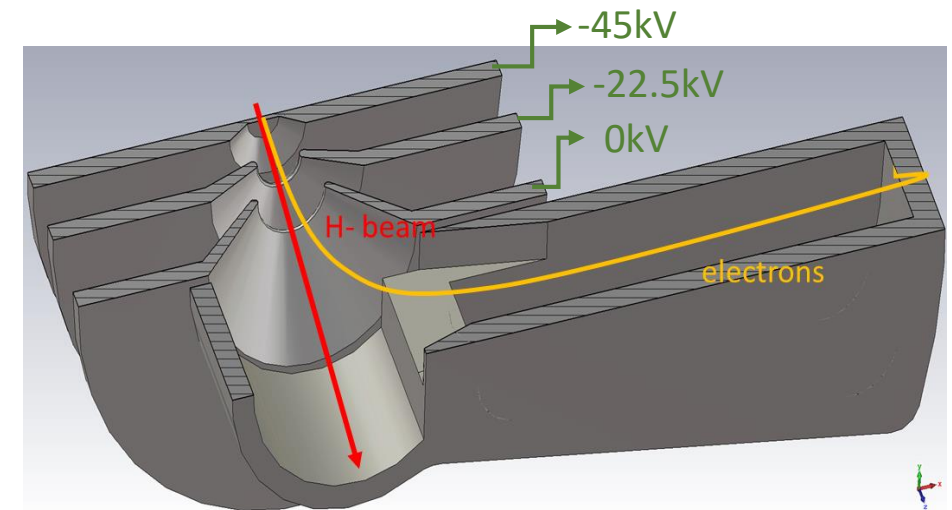


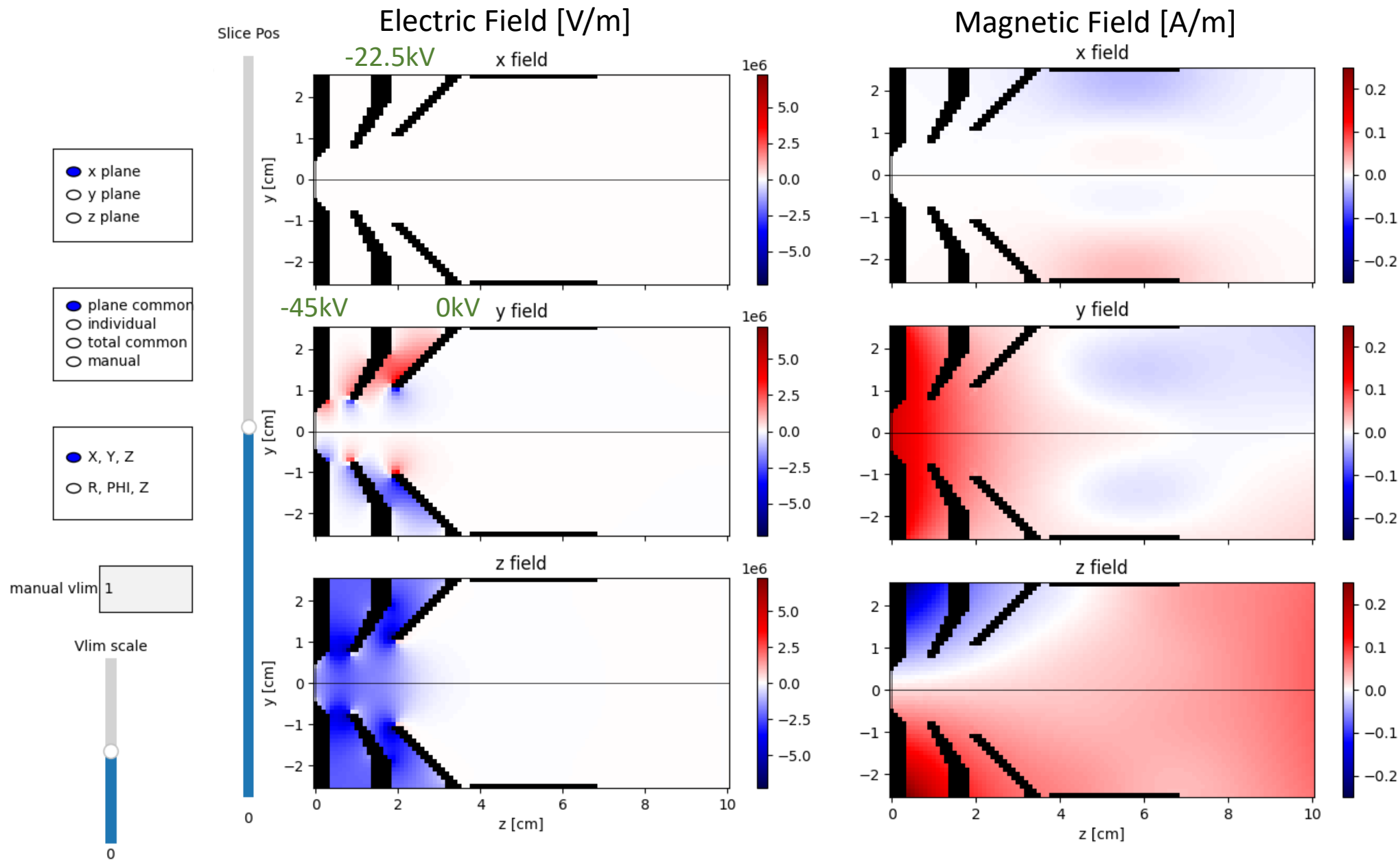
LINAC4 Ion Source



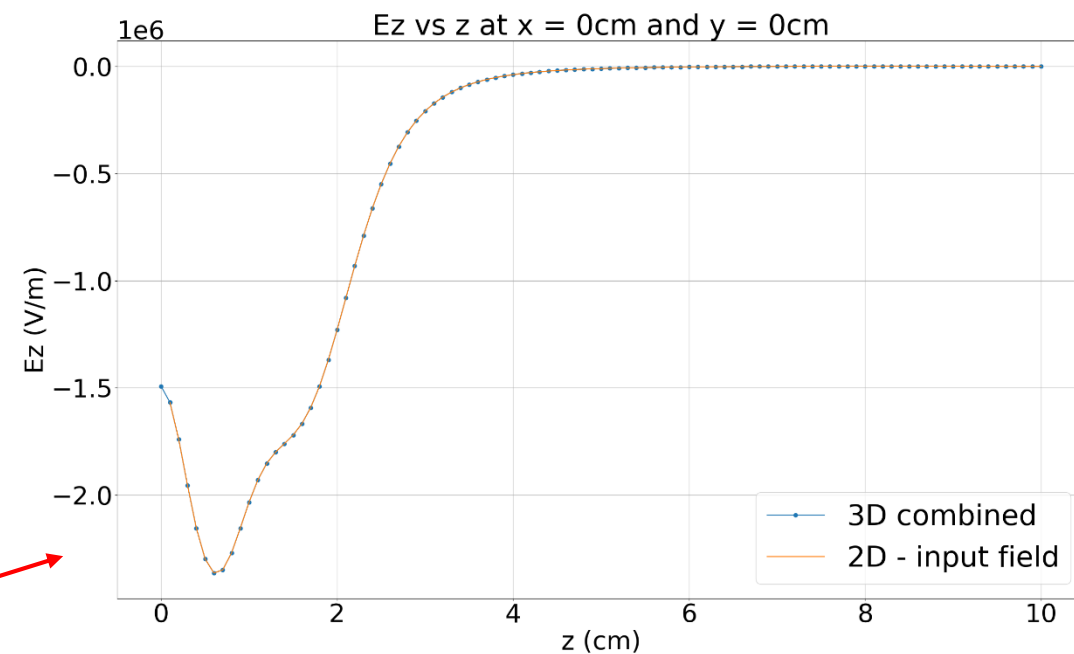
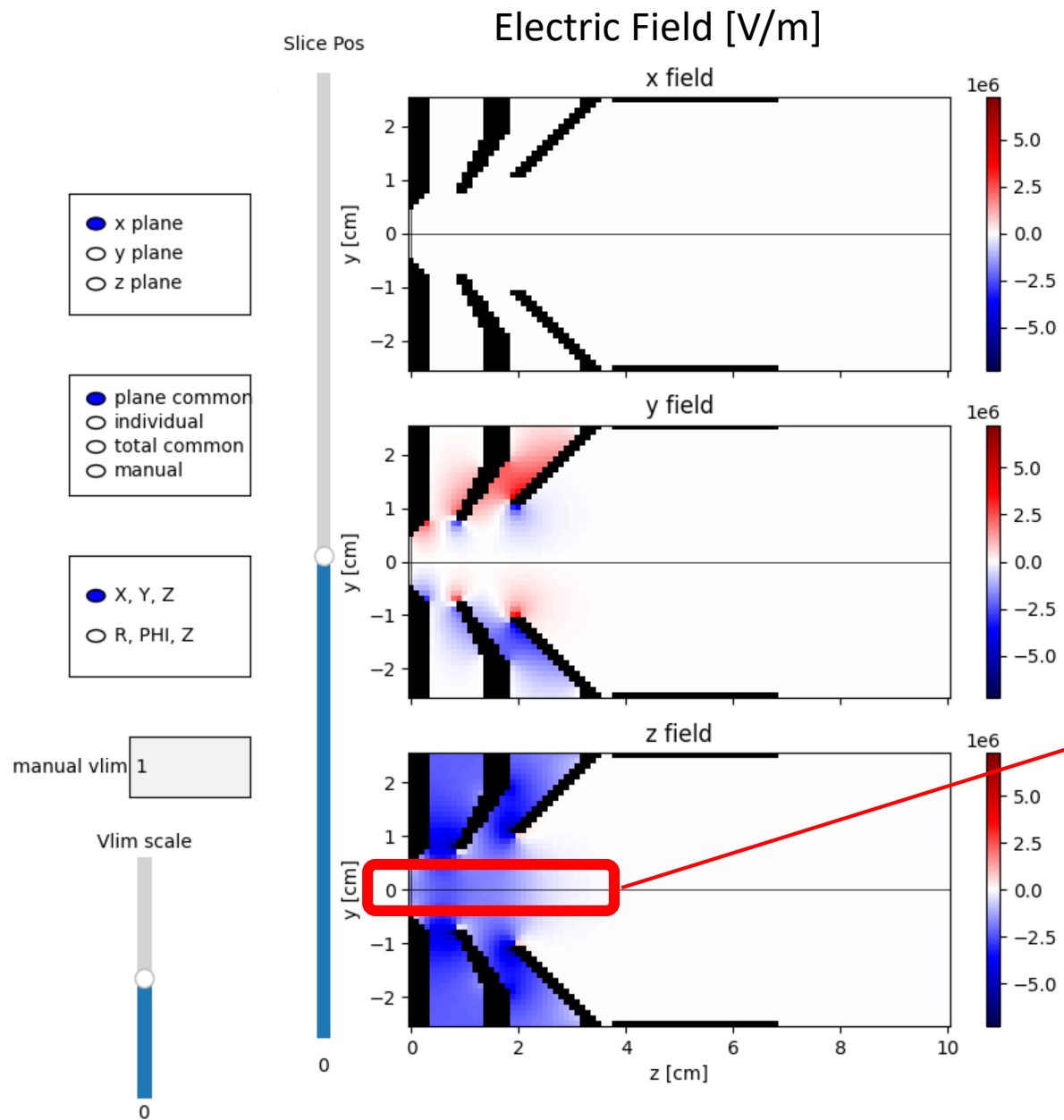
The relative strength between electric and magnetic field decides **beam quality**

Goal: Combine different **E** and **B** fields to simulate beam extraction systems



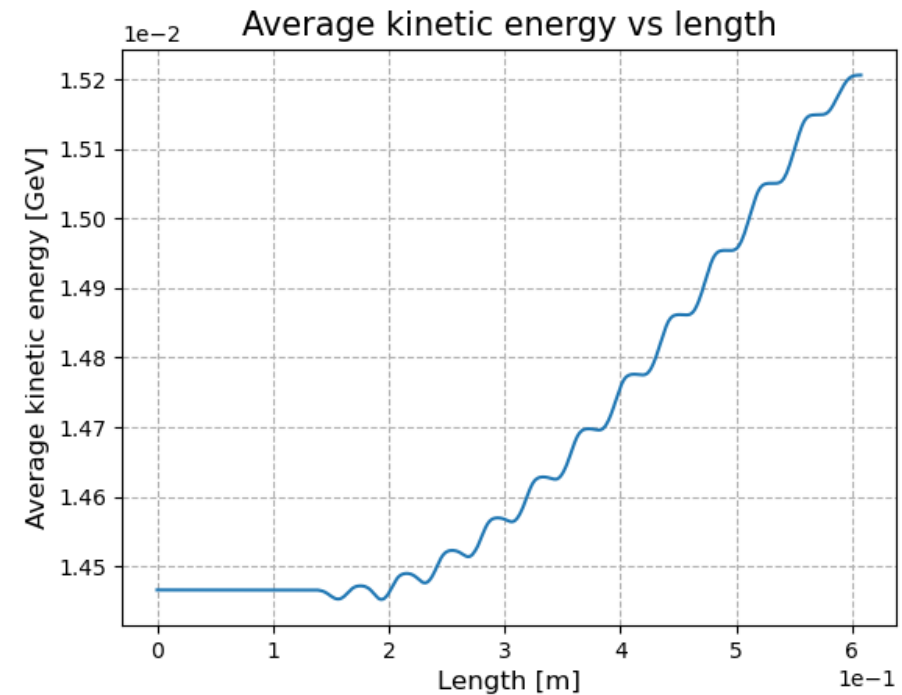
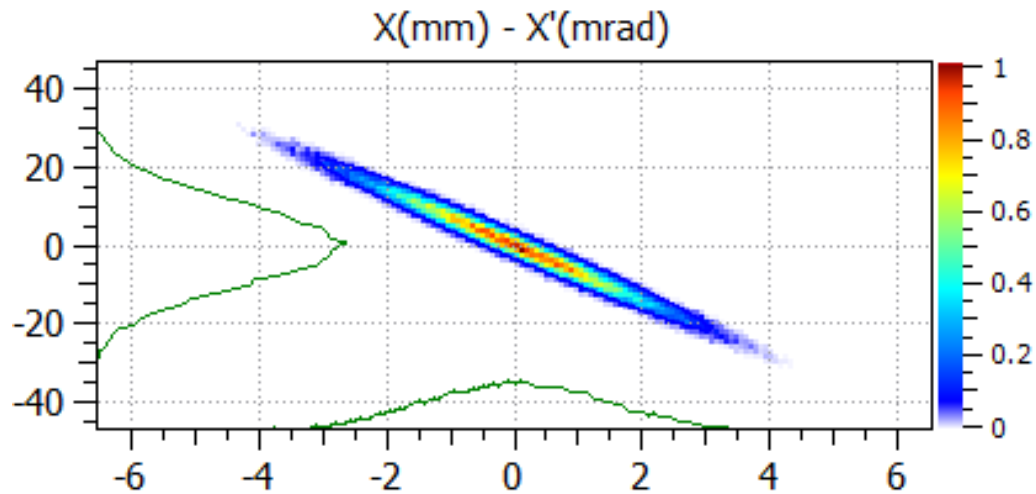


Combiner Results — ISO4



TRAVEL – Particle Tracking in Electric Field Map

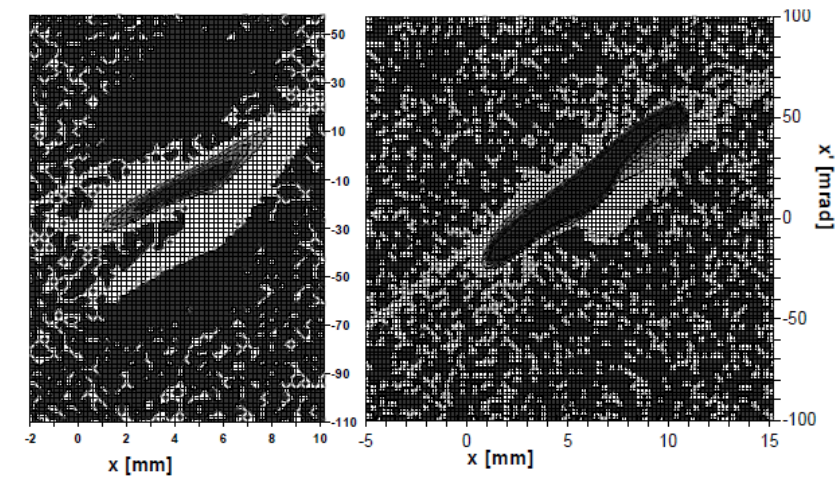
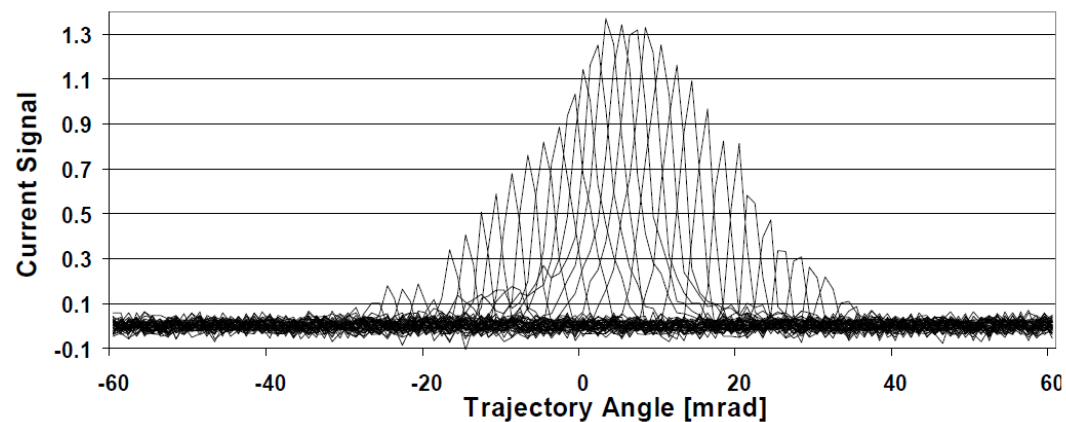
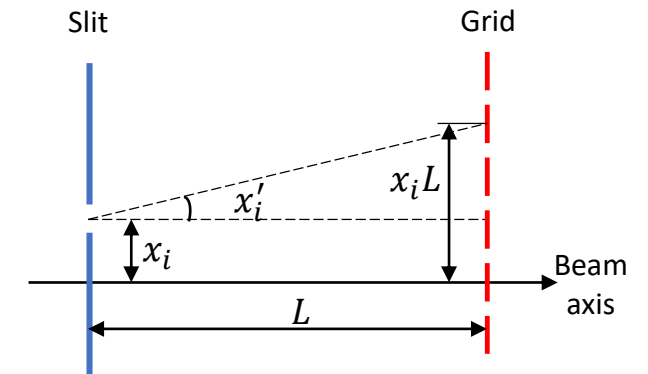
- Simulate particle trajectory using input beam and various elements of the structure



Particles traveling through an IH cavity

Emittance analysis: SCUBEEEx

- Beam emittance is measured at the test stand with **Slit – SEM Grid**
- Further outside the beam core, the particle flux drops to pure background, assumed to consist of only two components: the **noise** and the **bias**
- Applying a **simple threshold underestimates the emittance**
- SCUBEEEx – Exclude data far from the beam core:
 - Analyze and calculate Twiss parameters from moderately thresholded data
 - Estimate the elliptical exclusion
 - Determine bias from **beam-free background** data



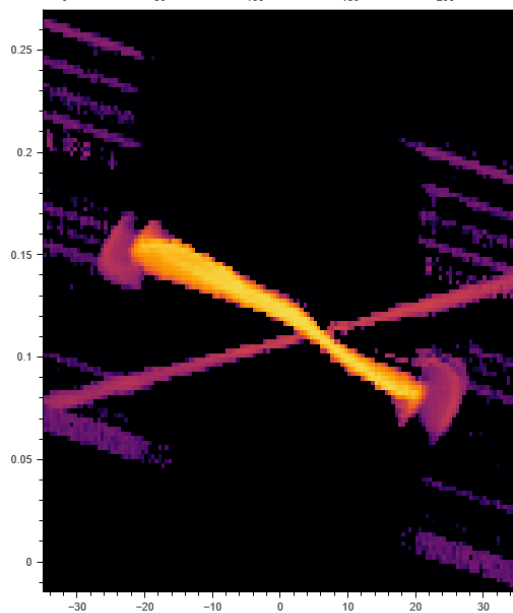
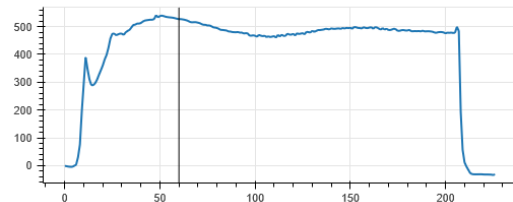
Current Progress

File load place holder

stop server

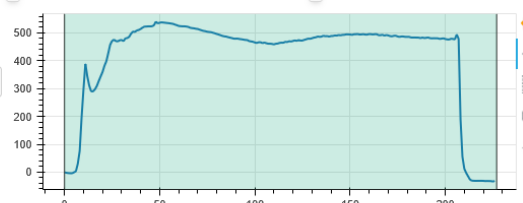
Measurement viewing

timeslot: 60
Measurement: 1

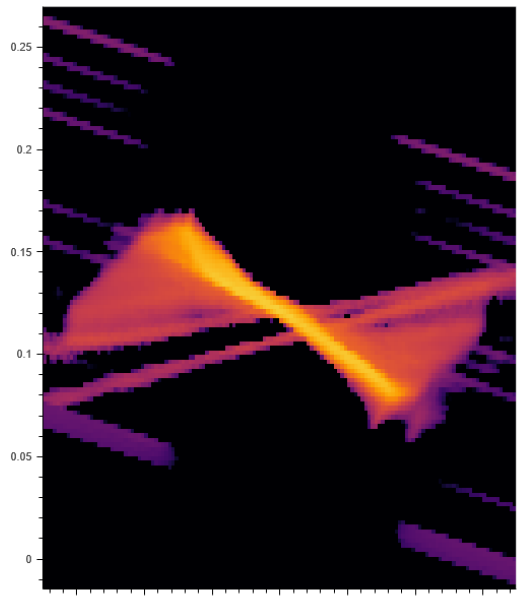


Measurement selection

Integrated time: 0 .. 227
Field 0 Field 1 Field 2

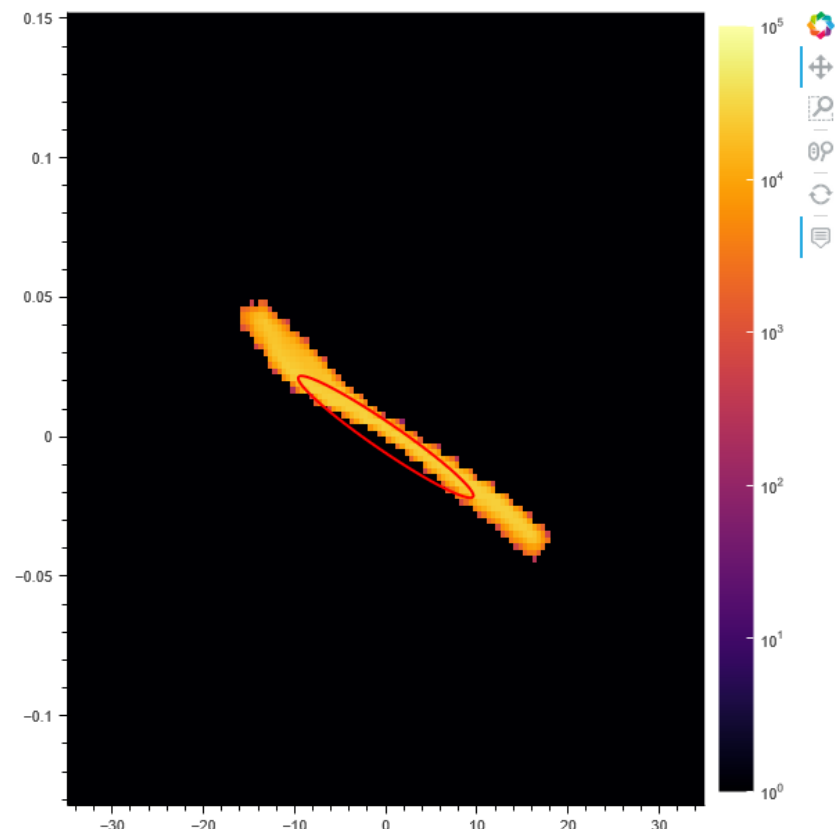


remove selected include selected reset selection

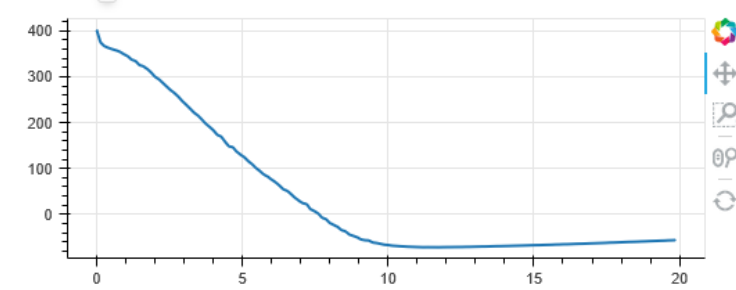


submit

Scubeex



init threshold %: 11



Future Works

- Complete SCUBEEEx analysis and the application interface
- Manual selection of excluded data – particularly useful to exclude H0 line
- Generate beam distribution from the analyzed data in DST, DAT (PATH/TRAVEL) and TXT (PATH/TRAVEL) formats
- Allow users to load, display and analyze/calculate (RMS, $N \times$ RMS, $N\%$ emittances, Twiss parameters) beam distributions in DST, DAT, and TXT formats

References

- Bazak, Betzalel & Weissman, L.. (2008). Minimum ellipse emittance analysis with SCUBEE code. Journal of Instrumentation. 3. T02001. 10.1088/1748-0221/3/02/T02001.
- Stockli, Martin & Welton, R. & Keller, R.. (2004). Self-consistent, unbiased root-mean-square emittance analysis. Review of Scientific Instruments. 75. 1646-1649. 10.1063/1.1695649.
- Stockli, Martin & P, Martin. (2006). Measuring and Analyzing the Transverse Emittance of Charged Particle Beams. AIP Conference Proceedings. 868. 10.1063/1.2401393.

Details: Exclusion analysis (SCUBEEx)

- Current evaluation of RMS emittance parameters takes into account statistical excursions and artifacts that are **unlikely to contain any real current signal**
- Exclude data far from the beam core:
 - Analyze and calculate Twiss parameters from moderately thresholded data
 - Estimate the elliptical exclusion
- The **average current measured outside the exclusion ellipse levels off** as soon as all real current signals are included (dashed curves on the plot)
- Determine bias from **beam-free background** data
- After subtracting the bias, the fraction of the beam inside the exclusion ellipse reaches unity for the same smallest ellipse size where the average outside current starts to level off (solid curves on the plot)
- SCUBEEx works best for beam distributions with **strong elliptical core**
- SCUBEEx should not be used for data with ghosts and artifacts because the incorrect bias subtraction can be very misleading

